Radiation damage in the electronic regime

Eduardo M. Bringa ebringa@yahoo.com

CONICET

Instituto de Ciencias Básicas, Universidad Nacional de Cuyo Mendoza, Argentina

SiMAF: Simulations in Materials Science, Astrophysics, and Physics

https://sites.google.com/site/simafweb

Non-adiabatic dynamics and radiation damage in nuclear materials

ICTP-IAEA, Trieste November 2011

COLLABORATORS:

J. Rodriguez-Nieva (Instituto Balseiro/MIT), D. Farkas, (VaTech), A. Caro (LANL), S. Kucheyev (LLNL), R. Baragiola, R.E. Johnson, T. Cassidy, L. Zhigilei (University of Virginia), D. Schwen (UIUC), R. Papaleo (PUC), N. Arista (Bariloche), C. Ruestes, E. Rim (U.N. Cuyo)



MENDOZA, LAND OF THE SUN AND THE GOOD WINE









- Background and Introduction
 - Track models
- Molecular Dynamics (MD) of damage in the electronic regime
 - Thermal Spikes, Two Temperature Models and Coulomb Explosions.
- Examples
 - Electronic sputtering, track formation: defects, phase change, craters & bumps.
- Conclusions and future outlook

Ion-solid interaction in the electronic regime





Microwires filling etched ion tracks Toulemonde et. al, NIMB **216** (2004) 1.



Desorption of complex molecules R.E. Johnson

Surface modification Sputtering [Brown, 1980], adatom generation, craters, hillocks, nanopatterning, etc.

Bulk radiation damage

Defects, amorphization [Fleischer, Price & Walker 1965], re-crystalization, phase change, mixing, chemical changes, *dE/dx* = Stopping Power. Energy loss per unit path length



 $dE/dx = (dE/dx)_{nuc} + (dE/dx)_{elec}$

 $(dE/dx)_{elec} = (dE/dx)_{ioniz} + (dE/dx)_{exc} + (dE/dx)_{ch-exch}$

Stopping Cross Section: **S**= (*dE/dx*)/n n is the density of the material



1 keV H⁺ \rightarrow **C** SRIM 2000 (Ziegler and Biersack) 10⁴ ions



dE/dx=5.2 eV/Å, 90% electronic. Range=135 Å. Max at 80 keV





1 MeV H⁺ → C SRIM 2000 (Ziegler and Biersack) 10⁴ ions dE/dx=5.4 eV/Å, 99.9% electronic. Range=11.5 μm. Max at 80 keV











 $(dE/dx)_{el}$ =3.5 keV/nm, $(dE/dx)_{nuc}$ =0.014 keV/nm, R_p= 1.8 µm (0.4 µm straggling) (dE/dx)_{el} has maximum at 6.5 MeV

1 MeV O→ UO₂ SRIM 2006 (Ziegler and Biersack) 10² ions This is a quick test. 100 ions too few for MC





 $(dE/dx)_{el}$ =1.5 keV/nm, $(dE/dx)_{nuc}$ =0.038 keV/nm, R_p= 0,8 µm (0.2 µm straggling) (dE/dx)_{el} has maximum at 6.5 MeV



 $(dE/dx)_{el}$ =1.5 keV/nm, $(dE/dx)_{nuc}$ =0.038 keV/nm, R_p= 0,8 µm (0.2 µm straggling) (dE/dx)_{el} has maximum at 6.5 MeV

Ion Range, or where does an ion stop?





Track dimensions and structure



Infra and Ultra Track





 $\begin{array}{l} \mathsf{R}_{\mathsf{infra}} = \mathsf{R}_{\mathsf{core}} \sim \mathsf{r}_{\mathsf{B}} \sim \mathsf{v}/\omega_{\mathsf{o}}, \\ \mathsf{h}\omega_{\mathsf{o}} = \mathsf{first} \; \mathsf{excitation} \; \mathsf{energy} \end{array}$

→ Velocity effect: damage different for the same *dE/dx*

 R_{ultra} ~ maximum range of $\delta e^{-} \propto E_{ion}$

Johnson & Schou, *Mat. Fys. Medd. Dan. Vid. Selsk.* **43** (1993) 403. Track radius R_e versus dE/dx for $Y_3Fe_5O_{12}$ Damage cross section: $A = \pi R_e^2$ Toulemonde *et. al*, NIMB **216** (2004) 1.

Not necessary to assume continuous track in MD (Schwen & Bringa, NIMB 2007)

"Effective" Stopping Power



 $(dE/dx)_{\text{effective}} = \alpha f (dE/dx) = \eta (dE/dx); \eta < 1$

 α = fraction deposited at the surface

f = *fraction that goes to relevant kinetic energy transfers, not spent in luminescence or in other excitations.*

Nuclear Sputtering

 $\alpha = \alpha (M_{tar}, M_{proj}, \Theta) ; f = 1$ (*dE/dx*)_{effective} = F_D(0)= $\alpha (dE/dx)_{nuclear}$

<u>Electronic Sputtering</u> *α*~1-0.5 (forward e⁻); *f* ~0.2-0.4 *f related to e-ph coupling* Typically: $\eta = \eta$ (v) $\eta \sim 0.2$ for "high" v $\eta \sim 0.5$ for "low" v

R. E. Johnson and J. Schou, Mat. Fys. Medd. Dan. Vid. Selsk. 43 (1993) 403.





Electronic Excitations

How do the atoms get extra kinetic energy from the electrons and from other atoms?

- $A^+ + A^+ \rightarrow A^+ + A^+ + \Delta E$ (Coulomb Repulsion)
- $(AB)^* \rightarrow A + B + \Delta E$ (Repulsive Decay)
- A^* + lattice $\rightarrow A^*$ + lattice + ΔE (Lattice Relaxation)
- $e(hot) + lattice \rightarrow e + lattice + \Delta E$ (e-Lattice Heating)
- $A^+ + e + e \rightarrow A^* + e(hot)$ (Dielectronic Recombination)
- $A^* + e \rightarrow A + e(hot) \rightarrow A + e + \Delta E$ (De-Excitation)

Other processes...

R. E. Johnson and J. Schou, Mat. Fys. Medd. Dan. Vid. Selsk. 43 (1993) 403.

Rough track formation time line





Primary ionizations, excitations and fast delta electrons are produced

Electrons thermalize, decay of excited states, neutralization, hole-hopping.

Sputtering, surface modification and defect creation

Luminescence, chemical reactions, defect relaxation

Surface/Bulk defect evolution requires "long" simulations: thermal ejection, recrystalization of simulated amorphous tracks, etc.

R. E. Johnson and J. Schou, Mat. Fys. Medd. Dan. Vid. Selsk. 43 (1993) 403.

Tracks in water (MC simulations of ionization)





 α particles

IAEA-TECDOC-799 Atomic and Molecular data for radiotherapy and radiation research, IAEA, Vienna, 1995



Protons

Track evolution and modeling





Many "analytic" models Coulomb Explosion (few flavors) Thermal Spikes (many flavors) Fleisher, Price and Walker, J. App. Phys. 36, 3645 (1965) Trautmann, Klaumunzer and Trinkaus, Phys. Rev. Lett. 85, 3648 (2000) MORE

but MD is often better

MD simulations can predict experimental track sizes [Devanatham *et al.*, NIMB (2008)] and sputtering [Bringa and Johnson, PRL 88, 165501, (2002)]





- Background and Introduction
 - Track models

• Molecular Dynamics (MD) of damage in the electronic regime

- Thermal Spikes, Two Temperature Models and Coulomb Explosions.

- Examples
 - Electronic sputtering, track formation: defects, phase change, craters & bumps.
- Conclusions and future outlook

MD Simulations of electronic damage



- Atomic Solid/Molecular solids
 Potentials: L-J, Morse, EAM, oxides, etc. U~0.1-10 eV
- Track: all/few atoms within a region with "radial" symmetry. Cylinder, Gaussian, etc. Size r_{cyl}
- Atoms in track can receive:

 -extra KE (prompt or ramped spike, or from TTM);
 compare with binding energy U;
 -extra charge Z (Coulomb explosion);
 -repulsive or anti-bonding potential.



$$\label{eq:exp} \begin{split} dE/dx = & \text{``effective''} \ dE/dx < (dE/dx)_{exp} \\ R_{cyl} = R_{track} \ (v, \ dE/dx, etc.) \end{split}$$

Variable time step + short-range potentials needed

MD simulation of electronic damage -II



- "Low" *dE/dx* simulations can be carried out with a "diluted" track.
- Velocity effect (i.e. a track size that differs for the same dE/dx and different velocity) can be taken into account with different $(dE/dx)_{eff}$ or r_{cvl} .
- For multi-component materials (polymers, alloys, oxides, water, etc.), it can use mass dependent velocity distributions.
- If main excitation decay channel is known, then it can be used instead of simple temperature distribution.
- Can add role of collision cascades, which would be important below/near tracking threshold, by adding a few recoils.
- Charge-state of projectile could be included using different $(dE/dx)_{eff}$.

MD track simulations offer a simple empirical way to incrementally add physical information, testing the relative importance of different contributing factors. They help understanding and possible guiding complex experiments, and building larger-scale models.

Combined Two Temperature Model (TTM) – MD SIMAE Analytical TTM from 1950s (Kaganov, Lifshits and Tantarov) $\begin{cases} C_{e}(T_{e})\frac{\partial T_{e}}{\partial t} = \frac{\partial}{\partial z}\left(K_{e}(T_{e})\frac{\partial}{\partial z}T_{e}\right) - G(T_{e} - T_{1}) + S(z, \\ C_{1}\frac{\partial T_{1}}{\partial t} = \frac{\partial}{\partial z}\left(K_{1}\frac{\partial}{\partial z}T_{1}\right) + G(T_{e} - T_{1}) & \longrightarrow MD \end{cases}$ MD : $m_{i} \frac{d^{2} \vec{r}_{i}}{dt^{2}} = \vec{F}_{i} + \xi m_{i} \frac{d \vec{r}_{i}}{dt}$ with $\xi = G (T_{e} - T_{1}) / \sum \frac{|\vec{p}_{i}|^{2}}{m}$ ION **Electronic energy deposition**

Toulemonde *et al.* (1994-2011): "Thermal spike" where heating is provided by secondary electrons → spike radius large and E/atom low → neglecting pressure effects is OK.
TTM (no MD → no pressure/surface) → successful to understand track size data; problems with sputtering data → use more accurate MD+TTM
MD+TTM first applied to lasers (Zhigilei, Ivanov, Urbassek, 2003), later applied to radiation damage (Duffy, Toulemonde, Nordlund, etc.): S(z,t) → S(r,t) o S(r,z,t)

Analytic Thermal Spike (TS) Models





Hydrodynamic Equations for a Thermal Spike also include mass and momentum effects



 $NC_{V}\partial T/\partial t = (1/r) \partial (rK_{T}T)/\partial r$ Jakas et al., several papers $-T(\partial p/\partial T)N \partial v/\partial r + visc.$ Alternative to TS: "shock models" $\partial v/\partial t = (1/NM) \partial p/\partial r$ which neglect heat diffusion effects $\partial N/\partial t = - \partial (Nv)/\partial r$ Bitensky & Parillis (1989) Fenyö & Johnson (1992) M = atomic mass, N = density Lesueur & Dunlop (1993) Few others Details: Ryazanov's talk Melting $C_{V} = \begin{cases} 6/2 k_{B} ; T < T_{f} \\ 3/2 k_{B} ; T_{f} < T \end{cases}$ MD: have to be careful with "localized" $C_V \rightarrow C_V + Q_{fus}/10$; if $T_{fus} - \Delta T < T < T_{fus} + \Delta T$ phase changes and temperature/pressure Thermal conductivity calculations.

 $K_T = (25 k_B/32\sigma_0)(k_BT/\pi M)^{1/2}, \sigma_0 = 1.151 Å$



- •Semi-analytical TS models do NOT give good description of energy transport and sputtering at high energy densities $(E_{exc} > U)$.
- •MD treats properly energy transport (thermal properties, phase transitions, pressure effects) and <u>surface</u>.
- •Assumptions about initial energy deposition are needed to understand experiments: electron-phonon coupling or effective *dE/dx*, initial track radius, velocity effects, etc.
- •Drawback: models takes few minutes, MD takes few days 🙂

First large-scale MD simulations of Coulomb Explosion (induced by slow-Highly Charged lons)



Hai-Ping Cheng and J. D. Gillaspy, PRB 55 (1997) 2628



FIG. 1. (Color) Snapshor of the time evolution of the Coulomb explosion process. Red and green spheres are used to indicate Si^m ions and Si atoms, respectively. This particular system consists of 365 ions. The initial Coulomb repulsive energy stored in the lemispherical region is about 87.3 keV. Between t=0 and 40 fb, the charged region expands significantly. At t=80 fb, over 100 ions are ejected from the surface, forming a pronounced tole. By 360 fb, the thele is much larger, and about 800 storm and ions are driven from the surface.



"Free" electrons screen the ions in the track "Static" screening: $V(r) = (Ze)^2 Exp(-r/a) / r$

Classical plasm a $a = v_{T}/\omega_{p}$ Debye screening Quantum plasm a $a \sim v_{F}/\omega_{p}$ Thom as-Ferm i screening

Use MC modeling with electron cross-sections/mean free paths to estimate time dependent screening

Coulomb explosion (CE) simulations





$$dJ/dx = A (Z_{eff}/v)^2 \ln(B v^2) \propto (dE/dx)_e$$

•Extremely difficult to determine neutralization times, both theoretically and experimentally

• If net repulsion is due to excited states, they may decay too fast, or they may diffuse far away before decaying.

MD Simulations of Coulomb Explosion

 $V(r_{ij})=V_{L-J}(r_{ij})+(Z_{i}Z_{j}/r_{ij}) Exp(-r_{ij}/a). r_{cut-Coul}=7 a$

depth of layer h > 2 $r_{_{cut-Coul}}$ $r_{_{track}}$ / $N_{_{ch-MAX}}$ = 2 charges/layer





Coulomb Explosion MD simulations



 $N_{ch}=2$, $a\sim l$, $r_{track}\sim l$, $\tau=1$ ps ~ 2 t_{D} charged atoms have twice the radius of neutral atoms Time = -2 ps 0.5 E(eV) 0.08 0.01



If neutralization is too fast there is no heating of the lattice!

Bringa, NIMB (2002)

Coulomb explosion leads to heating of the lattice as in TS



Bringa and Johnson, PRL 88, 165501 (2002)

Is there a thermal spike (TS)? YES!

SiMAF

Analyzing MD data, there is a clearly defined energetic track with: 1) $(dE/dx)_{eff} = A (dJ/dx)^2$ $Y_{MD-CE} = Y_{MD-TS}$ 2) r_{cvl} = Constant E⁻² 2nd layer 1st layer (dY/dE)/Y 0.1 (a) Coulomb, $\tau \approx \tau_{D}$ (b) Coulomb, $\tau \approx 20 \tau_{\rm p}$ (c) Thermal Spike 0.01 -0.1 10 E/U Coulomb Prompt **Spike** Coulomb

Old idea: "Thermalized" ion explosion model



- L. E. Seiberling, J. E. Griffith, and T. A.Tombrello, Rad. Eff. **52** (1980) 201 Ryazanov *et al.* have similar model, including coupling to MD
- Coulomb explosion heats up the atoms at the track.
- Sputtering as in the thermal spike model.
 - $Y \sim \Delta A \Delta t$ flux(T) $\sim \pi r_{cyl}^2 (r_{cyl}^2/4K)$ flux(T)

 $Y^{(dJ/dx)^4}$, $Y^{(dJ/dx)exp[-Ur_{cvl}^2/(dJ/dx)^2]$



Fig. 4. Sputtering yield data versus beam energy per atomic mass unit for chlorine ions incident on UF₄ from a "stripped" experiment.⁴ Also shown are sputtered ion yields for sulfur ions on CsI and ergosterol targets (23). $S(M^+)$ refers to the sputtering yield of (ergosterol)⁺ ions. The curve is a fit to $(dJ/dx)^4$ (see text, section 2).

Summary of recent MD simulations of electronic damage



- Many papers using instantaneous energy deposition in cylindrical track (Urbassek & Johnson 1994, Bringa *et al.*, PRL, PRB, NIMB, Surf. Sci, etc. 1996-2011).
- Analytical models OK at low energy density but do not work at high energy density: pressure + surface effects + Non-LTE are a problem (Bringa et al., NIMB + PRB).
- Hydrodynamic model fit to MD works very well (Jakas et al., PRB,NIMB,1999-2002).
- Simulation results for sputtering of Lennard-Jones model solid agree with simulations for more complex materials (Bringa *et al.*, Surf. Sci. 2000; Tucker *et al.*, NIMB 2005).
- Difficult to connect experimental *dE/dx* to energy deposited in simulation (Toulemonde, Tombrello, Szenes, etc., mostly in NIMB and PRB).
- Can use more complex models of track heating, for instance TTM (Toulemonde *et al.*, many papers PRB/NIMB).
- Results from Toulemonde, Beuve, and co-workers show variation of results when adding temporal and spatial effects in track heating (PRB, NIMB 2001-2008).
- TS useful for track formation simulations in bulk (Devanathan *et al.*; NIMB 2007, Schwen & Bringa, NIMB 2007; Kluth *et al.* PRL 2008, Duffy, several papers 2006-2010).
- Useful model: cluster-induced nuclear sputtering and damage (Brunelle NIMB 2004).





Given all the approximations and limitations involved ...

Can we hope for quantitative agreement between MD and experiments when electronic effects are important?

OR ...



Is MD just pretty movies and pictures?





- Background and Introduction
 - Track models
- Molecular Dynamics (MD) of damage in the electronic regime
 - Thermal Spikes, Two Temperature Models and Coulomb Explosions.

Examples

- Electronic sputtering, track formation: defects, phase change,

craters & bumps

Conclusions and future outlook

Example I: Electronic sputtering of solid oxygen





Includes "velocity effect" in track size

Example II: Cratering in PMMA







Experiments by R. Papaléo *et al.* (several papers)

Crater size (R. Papaléo et al.) agrees extremely well with MD





Bringa et al., PRB, NIMB

Example III: Can we create nano-holes? YES



ION



If the thin-film is too thick, the track not wide enough, or the energy deposited not high enough, only a crater is formed (no hole)

4 times more energy in the track (other parameters the same) → hole is formed! remains stable and cool after 100 ps

TEM observation of double nano-craters



Follstaedt, Rossi and Doyle (SNL): Au (374 MeV) \rightarrow sapphire



Follstaedt et al., NIMB 2006

symmetry in crater size possibly due to δe^{-} asymmetry?

Example IV: Tracks in ta-C create conducting nano-wires





Hillock formation (2 10⁶ atoms, modified Brenner potential)





Schwen & Bringa, submitted (2011)



Example V: Amorphization of forsterite (Mg₂SiO₄) by electronic effects





MD simulations of amorphization

P. Durham (LLNL/Cincinnati), R. Devanatham, R. Corrales (PNNL)



DL_POLY with parallel domain decomposition, 32-128 CPUs, 10⁴-1.25 10⁶ atoms.
Buckingham potential + SPME
Thermal spike model
New local order parameter to detect amorphization



4000 • .20 ps 3500 1.08 ps **Temperature (K)** 2500 2000 1500 3.88 ps × 13.88 ps • 28.88 ps + 73.88 ps 1000 500 0 75 0 25 50 100 125 150 Radial Distance (A) 13.9 ps

Devanatham et al., NIMB (2007)

Silicates can be amorphized by cosmic rays





E.M. Bringa et al., Astrophys. J. (2007)

Example VI: Sputtering yield of porous solids (Rodriguez-Nieva et al., Astrophysical J. Letters, 2011)



There are no reliable analitic or semi-analitic models of sputtering as a function of density for porous materials. "Exception": Johnson, Icarus **78**, 206 (1989).

What can we expect? (Assume dE/dx does not depend strongly on geometry)

- 1) Fewer electronic excitations \rightarrow lower energy density \rightarrow lower yield
- 2) Larger effective surface \rightarrow higher yield
- 3) Atoms can be ejected from depth thanks to pores ightarrow

if sticking is large \rightarrow lower yield; if sticking is low \rightarrow larger yield.





Sputtering from a "dense" solid





Sputtering yield from nanofoam ~sputtering for bulk solid





CONCLUSIONS



- Simple models can account for many experimental results!
- But **cannot** account for many other experimental results
- Poor understanding of: synergy between nuclear and electronic dE/dx + nuclear reactions, dE/dx at surfaces or nanostructures (islands, foams, nanoprecipitates, interfaces, etc.), charge-state effects (in dE/dx, ion ejection, charge exchange for both target & projectile, etc.), dE/dx for cluster projectiles, statistics of dE/dx and track size, etc.
- Beware of limitations due to system size and total simulated time!
- Empirical potentials offer severe constrains and have to be used with care:
 where they were not intended to be used (phase transitions; high P/T; core-shell potentials for oxides problematic in radiation simulations).
 - where classical MD does not work properly (high P/T).

FUTURE- I



• Multi-scale models needed for improved simulations:

-coupling to FEM for larger system size;

-more general accelerated dynamics or KMC for defect evolution;

-coupling to MC/DFT/TB/TDDFT/naTB for better excitation treatment

-empirical potentials which depend dynamically on electronic state (high P/T, excitations, electron density – Khakshouri *et al.*, PRB 2008-), etc.

- Better ion-electron models are already available and are discussed by several presentations in this workshop (Artacho, Caro, Correa, Fisher, Foulkes, Lu). The electron Force Field potential (eFF, Su & Goddard, PRL 2007) is another option for light elements.
- Still lacking reliable and efficient models for **swift heavy ions**.

FUTURE- II



- More CPU/GPU processing for MD parameter sweeping will speed up research, allowing for improved models, better potentials, and increasing statistics and parameter sweeping.
 LAMMPS/DL_POLY, etc. already have GPU versions.
- Need more links to experiments: measurement of surface and bulk defects (AFM/STM/TEM simulation –Victoria's talk-), IR spectra (Caturla *et al.*), X-ray diffraction simulation, mechanical properties, etc.
- Similarities with electronic excitations by photons (UV, lasers) should be exploited.
- Need more experiments!